ON Semiconductor

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ON Semiconductor®

FDD14AN06LA0-F085

N-Channel PowerTrench® MOSFET 60V, 50A, 14.6m Ω

Features

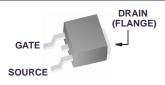
- $r_{DS(ON)} = 12.8 \text{m}\Omega \text{ (Typ.)}, V_{GS} = 5 \text{V}, I_D = 50 \text{A}$
- $Q_a(tot) = 25nC (Typ.), V_{GS} = 5V$
- · Low Miller Charge
- Low Q_{RR} Body Diode
- UIS Capability (Single Pulse and Repetitive Pulse)
- Qualified to AEC Q101
- RoHS Compliant



Applications

- · Motor / Body Load Control
- ABS Systems
- Powertrain Management
- Injection Systems
- DC-DC converters and Off-line UPS
- · Distributed Power Architectures and VRMs
 - Primary Switch for 12V and 24V systems

Formerly developmental type 83557





TO-252AA FDD SERIES

MOSFET Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Ratings	Units
V_{DSS}	Drain to Source Voltage	60	V
V _{GS}	Gate to Source Voltage	±20	V
	Drain Current		
	Continuous ($T_C < 100^{\circ}$ C, $V_{GS} = 10$ V)	50	А
I_D	Continuous ($T_C < 80^{\circ}$ C, $V_{GS} = 5V$)	50	А
	Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 5V$, with $R_{\theta JA} = 52^{\circ}C/W$)	9.5	А
	Pulsed	Figure 4	А
E _{AS}	Single Pulse Avalanche Energy (Note 1)	55	mJ
	Power dissipation	125	W
P_{D}	Derate above 25°C	0.83	W/°C
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C

Thermal Characteristics

$R_{\theta JC}$	Maximum Thermal Resistance Junction to Case TO-252	1.2	°C/W
$R_{\theta JA}$	Maximum Thermal Resistance Junction to Ambient TO-252, 1in ² copper pad area	52	°C/W

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Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD14AN06LA0	FDD14AN06LA0-F085	TO-252AA	330mm	16mm	2500 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

Parameter	Test C	onditions	Min	Тур	Max	Units
acteristics						
Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_C$	_{GS} = 0V	60	-	-	V
Zero Gate Voltage Drain Current	$V_{DS} = 50V$		-	-	1	^
	$V_{GS} = 0V$	$T_{\rm C} = 150^{\rm o}{\rm C}$	-	-	250	μΑ
Gate to Source Leakage Current	$V_{GS} = \pm 20V$		-	-	±100	nA
	Drain to Source Breakdown Voltage Zero Gate Voltage Drain Current	Drain to Source Breakdown Voltage $I_D = 250\mu A$, V_C Zero Gate Voltage Drain Current $V_{DS} = 50V$ $V_{GS} = 0V$	Drain to Source Breakdown Voltage $I_D = 250\mu A$, $V_{GS} = 0V$ Zero Gate Voltage Drain Current $V_{DS} = 50V$ $V_{GS} = 0V$ $V_{CS} = 150^{\circ} C$	Drain to Source Breakdown Voltage $I_D = 250\mu A$, $V_{GS} = 0V$ 60 Zero Gate Voltage Drain Current $V_{DS} = 50V$ - $V_{GS} = 0V$ $V_{CS} = 150^{\circ}C$ -		

On Characteristics

V _{GS(TH)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 250\mu A$	1	-	3	V
r _{DS(ON)}	Drain to Source On Resistance	$I_D = 50A, V_{GS} = 10V$	-	0.0102	0.0116	4
		$I_{D} = 50A, V_{GS} = 5V$	-	0.0128	0.0146	
		$I_D = 50A, V_{GS} = 5V,$ $T_J = 175$ °C	-	0.028	0.033	

Dynamic Characteristics

C _{ISS}	Input Capacitance	051/ 1/	.,	-	2810	-	pF
C _{OSS}	Output Capacitance		$V_{DS} = 25V, V_{GS} = 0V,$ f = 1MHz		270	-	pF
C _{RSS}	Reverse Transfer Capacitance	1 - 1101112			115	-	pF
$Q_{g(TOT)}$	Total Gate Charge at 5V	$V_{GS} = 0V \text{ to } 5V$			25	32	nC
$Q_{g(TH)}$	Threshold Gate Charge	$V_{GS} = 0V \text{ to } 1V$	$V_{DD} = 30V$	-	2.7	3.5	nC
	Gate to Source Gate Charge		$I_D = 50A$	-	9.7	-	nC
Q _{gs} Q _{gs2}	Gate Charge Threshold to Plateau		$I_g = 1.0 \text{mA}$	-	7.0	-	nC
Q_{gd}	Gate to Drain "Miller" Charge			-	8.7	-	nC

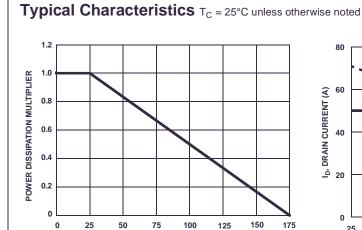
Switching Characteristics $(V_{GS} = 5V)$

t _{ON}	Turn-On Time	$V_{DD} = 30V, I_{D} = 50A$ $V_{GS} = 5V, R_{GS} = 5.1\Omega$	-	-	218	ns
t _{d(ON)}	Turn-On Delay Time		-	14	-	ns
t _r	Rise Time		-	132	-	ns
t _{d(OFF)}	Turn-Off Delay Time		-	27	-	ns
t _f	Fall Time		-	47	-	ns
t _{OFF}	Turn-Off Time		-	-	111	ns

Drain-Source Diode Characteristics

V _{SD}	Source to Drain Diode Voltage	I _{SD} = 50A	-	-	1.25	V
		I _{SD} = 25A	-	-	1.0	V
t _{rr}	Reverse Recovery Time	$I_{SD} = 50A$, $dI_{SD}/dt = 100A/\mu s$	-	-	30	ns
Q _{RR}	Reverse Recovered Charge	$I_{SD} = 50A$, $dI_{SD}/dt = 100A/\mu s$	-	-	24	nC

Notes: 1: Starting $T_J = 25^{\circ}C$, L = 70uH, $I_{AS} = 40A$.



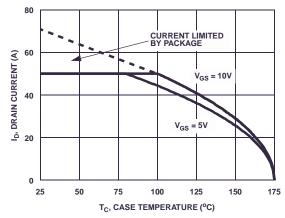


Figure 1. Normalized Power Dissipation vs **Ambient Temperature**

T_C, CASE TEMPERATURE (°C)

Figure 2. Maximum Continuous Drain Current vs **Case Temperature**

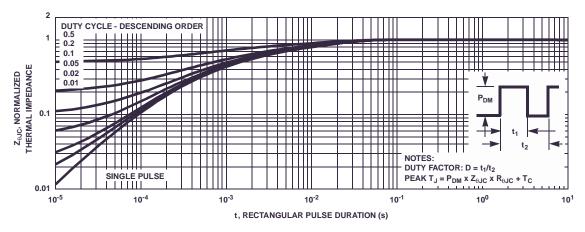


Figure 3. Normalized Maximum Transient Thermal Impedance

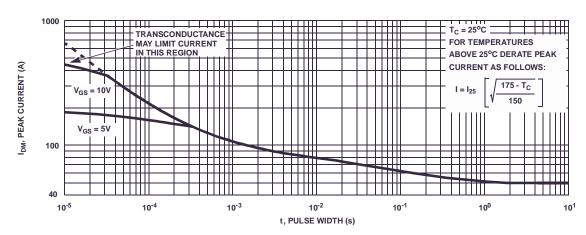
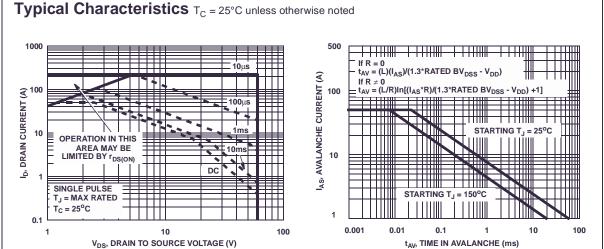


Figure 4. Peak Current Capability



100

Figure 5. Forward Bias Safe Operating Area

NOTE: Refer to ON Semiconductor Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching
Capability

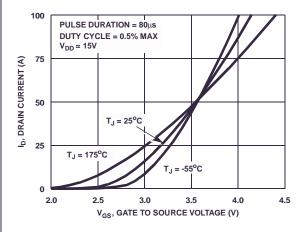
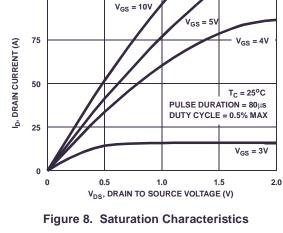


Figure 7. Transfer Characteristics



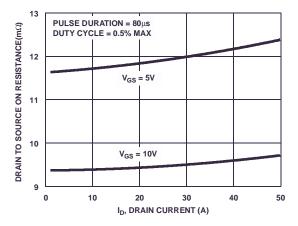


Figure 9. Drain to Source On Resistance vs Drain Current

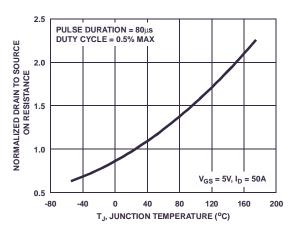


Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature

Typical Characteristics $T_C = 25$ °C unless otherwise noted

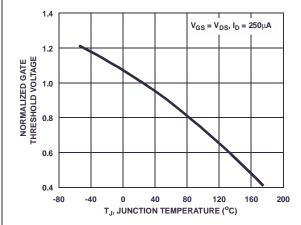


Figure 11. Normalized Gate Threshold Voltage vs Junction Temperature

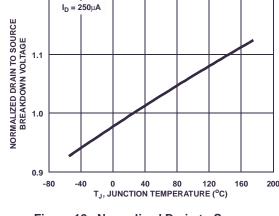


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

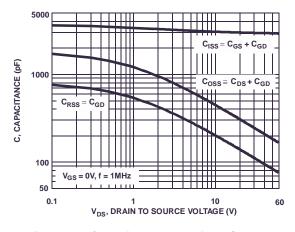


Figure 13. Capacitance vs Drain to Source Voltage

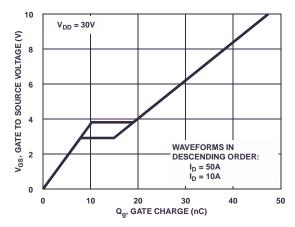


Figure 14. Gate Charge Waveforms for Constant Gate Currents

Test Circuits and Waveforms

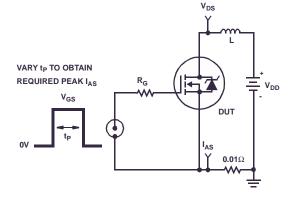


Figure 15. Unclamped Energy Test Circuit

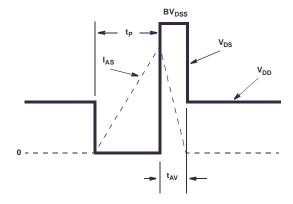


Figure 16. Unclamped Energy Waveforms

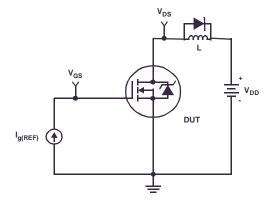


Figure 17. Gate Charge Test Circuit

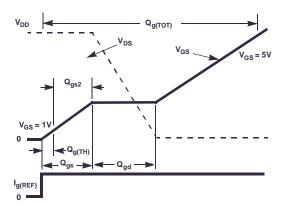


Figure 18. Gate Charge Waveforms

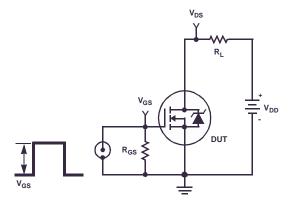


Figure 19. Switching Time Test Circuit

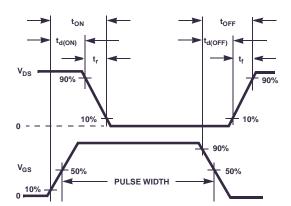


Figure 20. Switching Time Waveforms

Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}} \tag{EQ. 1}$$

In using surface mount devices such as the TO-252 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- 6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

ON Semiconductor provides thermal information to assist the designer's preliminary application evaluation. Figure 21

defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the ON Semiconductor device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 33.32 + \frac{23.84}{(0.268 + Area)}$$
 (EQ. 2)

Area in Inches Squared

$$R_{\theta JA} = 33.32 + \frac{154}{(1.73 + Area)}$$
 (EQ. 3)

Area in Centimeters Squared

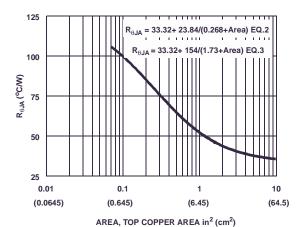
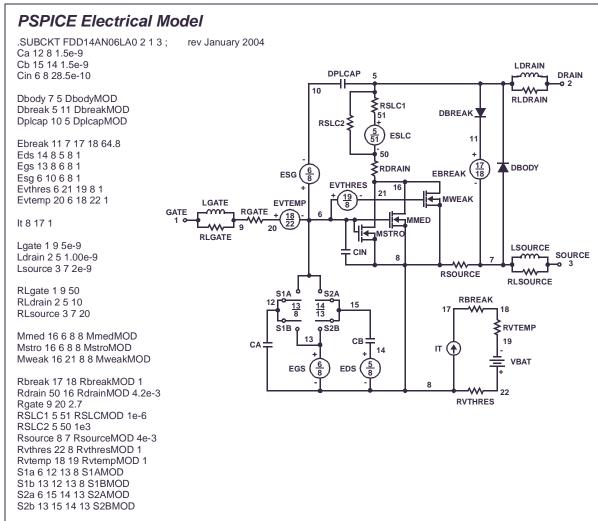


Figure 21. Thermal Resistance vs Mounting
Pad Area



Vhat 22 19 DC 1

ESLC 51 50 VALUE={(V(5,51)/ABS(V(5,51)))*(PWR(V(5,51)/(1e-6*200),3))}

.MODEL DbodyMOD D (IS=15e-12 RS=3.2e-3 N=1.05 TRS1=1.5e-3 TRS2=1e-6

+ CJO=10e-10 TT=1.5e-8 M=0.58 IKF=15.00 XTI=3)

.model dbreakmod d (RS=1e-1 TRS1=1.12e-3 TRS2=1.25e-6)

.MODEL DplcapMOD D (CJO=80e-11 IS=1e-30 N=10 M=0.57)

.MODEL MmedMOD NMOS (VTO=2 KP=8 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=2.7)

.MODEL MstroMOD NMOS (VTO=2.45 KP=105 IS=1e-30 N=10 TOX=1 L=1u W=1u)

.MODEL MweakMOD NMOS (VTO=1.61 KP=0.04 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=27 RS=0.1)

.MODEL RbreakMOD RES (TC1=0.92e-3 TC2=-0.35e-6)

.MODEL RdrainMOD RES (TC1=7.92e-3 TC2=3.4e-5)

.MODEL RSLCMOD RES (TC1=2.8E-3 TC2=1E-7)

.MODEL RsourceMOD RES (TC1=4.0e-3 TC2=1e-6)

.MODEL RvthresMOD RES (TC1=-2.5e-3 TC2=-1e-5)

.MODEL RvtempMOD RES (TC1=-2.3e-3 TC2=1.5e-6)

.MODEL S1AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-4 VOFF=-3)

.MODEL S1BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-3 VOFF=-4)

.MODEL S2AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-2.5 VOFF=-0.5)

.MODEL S2BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-0.5 VOFF=-2.5)

.ENDS

Note: For further discussion of the PSPICE model, consult A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.

SABER Electrical Model REV January 2004 template FDD14AN06LA0 n2,n1,n3 electrical n2,n1,n3 var i iscl dp..model dbodymod = (isl=15e-12,rs=3.2e-3,nl=1.05,trs1=1.5e-3,trs2=1e-6,cjo=10e-10,tt=1.5e-8,m=0.58,ikf=15.00,xti=3) dp..model dbreakmod = (rs=1e-1.trs1=1.12e-3.trs2=1.25e-6) dp..model dplcapmod = (cjo=80e-11,isl=10e-30,nl=10,m=0.57) $m..model mmedmod = (type=_n, vto=2, kp=8, is=1e-30, tox=1)$ m..model mstrongmod = (type=_n,vto=2.45,kp=105,is=1e-30, tox=1) m..model mweakmod = (type=_n,vto=1.61,kp=0.04,is=1e-30, tox=1,rs=0.1) I DRAIN sw_vcsp..model s1amod = (ron=1e-5,roff=0.1,von=-4,voff=-3) DPLCAP DRAIN sw_vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-3,voff=-4) 10 sw_vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-2.5,voff=-0.5) RLDRAIN sw_vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=-0.5,voff=-2.5) ≸RSLC1 c.ca n12 n8 = 1.5e-951 RSLC2 ≥ c.cb n15 n14 = 1.5e-9ISCL c.cin n6 n8 = 28.5e-10DBREAK 1 dp.dbody n7 n5 = model=dbodymod **≨**RDRAIN dp.dbreak n5 n11 = model=dbreakmod 6 8 ESG (DBODY dp.dplcap n10 n5 = model=dplcapmod **EVTHRES** 21 MWFAK LGATE **EVTEMP** spe.ebreak n11 n7 n17 n18 = 64.8 _{GATE} **RGATE** 1822 spe.eds n14 n8 n5 n8 = 1 EBREAK MMED ₩-20 spe.egs n13 n8 n6 n8 = 1 **■**MSTR RLGATE spe.esg n6 n10 n6 n8 = 1 CIN spe.evthres n6 n21 n19 n8 = 1 SOURCE spe.evtemp n20 n6 n18 n22 = 1 RSOURCE RLSOURCE i.it n8 n17 = 1RBREAK <u>14</u> 13 17 I.lgate n1 n9 = 5e-9 18 I.ldrain n2 n5 = 1.00e-9**₹**RVTEMP o S2B S₁B I.Isource n3 n7 = 2e-9СВ 19 IT 14 res.rlgate n1 n9 = 50 VRAT 5 8 res.rldrain n2 n5 = 10 **FGS** FDS res.rlsource n3 n7 = 20 **RVTHRES** m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u m.mweak n16 n21 n8 n8 = model=mweakmod, l=1u, w=1u res.rbreak n17 n18 = 1, tc1=0.92e-3,tc2=-0.35e-6 res.rdrain n50 n16 = 4.2e-3, tc1=7.92e-3,tc2=3.4e-5 res.rgate n9 n20 = 2.7 res.rslc1 n5 n51 = 1e-6, tc1=2.8e-3,tc2=1e-7 res.rslc2 n5 n50 = 1e3res.rsource n8 n7 = 4e-3, tc1=4.0e-3,tc2=1e-6 res.rvthres n22 n8 = 1, tc1=-2.5e-3,tc2=-1e-5 res.rvtemp n18 n19 = 1, tc1=-2.3e-3,tc2=1.5e-6 sw vcsp.s1a n6 n12 n13 n8 = model=s1amod sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { i (n51->n50) +=iscl (v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/200))**3))

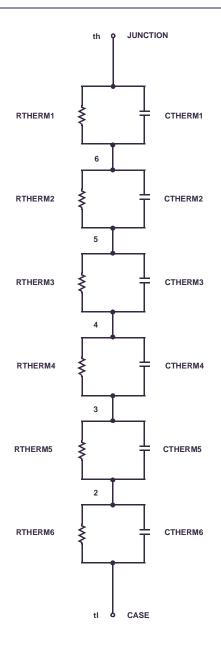
REV January 2004 FDD14AN06LA0T CTHERM1 TH 6 2.5e-3 CTHERM2 6 5 3e-3 CTHERM3 5 4 4e-3 CTHERM4 4 3 7e-3 CTHERM5 3 2 8.2e-3 CTHERM6 2 TL 5e-2 RTHERM1 TH 6 4.2e-2 RTHERM2 6 5 8.4e-2

SABER Thermal Model

RTHERM3 5 4 1.04e-1

RTHERM4 4 3 1.14e-1 RTHERM5 3 2 2.74e-1 RTHERM6 2 TL 3.44e-1

rtherm.rtherm6 2 tl =3.44e-1



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